

The Effect of Charge Limits on Particle Charge Distributions in Nanodusty Plasmas

Romain Le Picard and Steven L. Girshick

Dept. of Mechanical Engineering

University of Minnesota, Minneapolis, MN 55455, USA

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Outline

- Introduction
- Particle charge limits
- Particle charge distributions
- Analytical model for charge distributions with charge limits
- The particle-charge-limited regime
- Conclusions

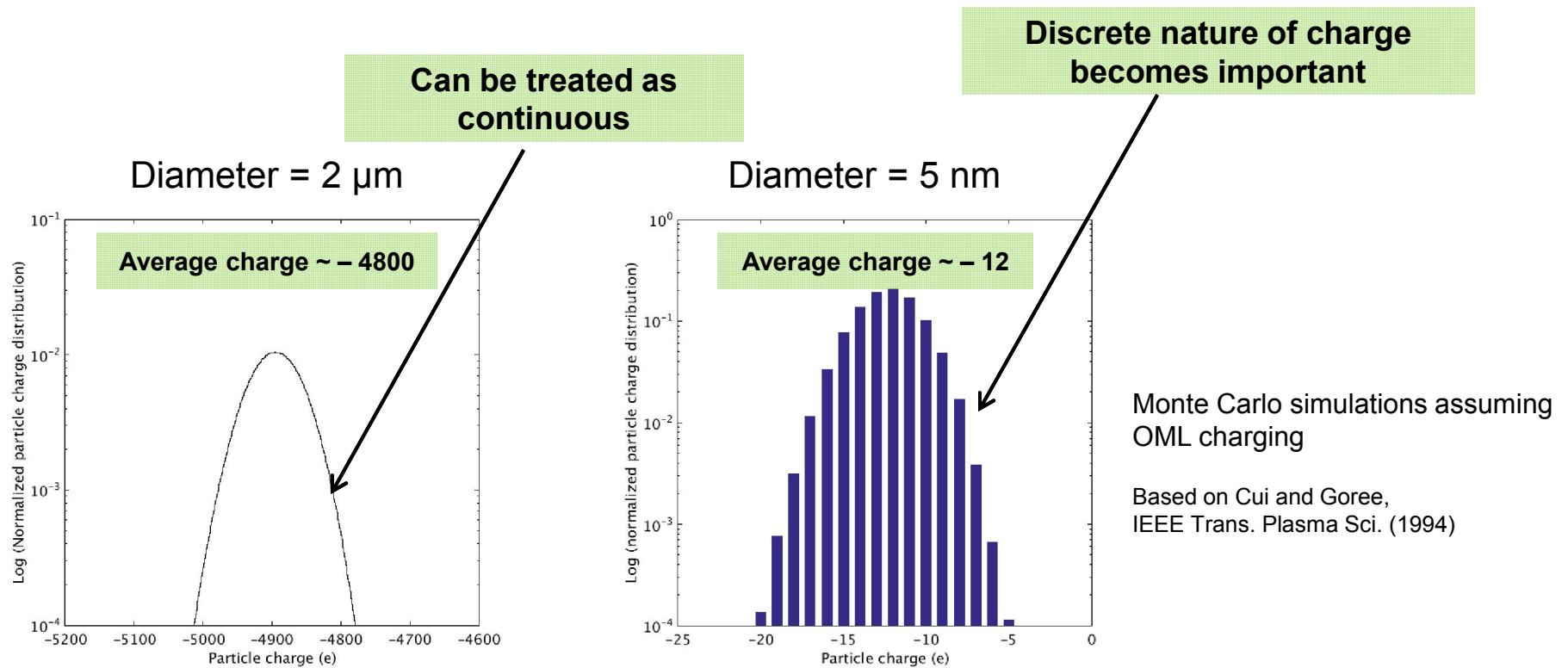
Motivation

The amount of charge a dust particle can hold is limited, but this has never been taken into account in previous models of charge distributions in dusty plasmas.

Introduction

- Particle charge fluctuates due to discrete charging events

⇒ Causes particles to exhibit a **charge distribution**



Particle charge limits

Maximum number of electrons that can coexist on a given particle

- **Electron field emission**

Draine and Sutin, Astrophysical Journal, 1987

$$q_{\text{lim}} = 1 + 0.7 \frac{R^2}{1 \text{ nm}^2}$$

- **Effective electron affinity**

Based on Boufendi, Stoffels, and Stoffels, 1999

Bulk electron affinity

$$q_{\text{lim}} = A_{\infty} \frac{4\pi\epsilon_0 R}{e^2} + \frac{3}{8}$$

- **Rayleigh limit**

Rayleigh, Phil. Mag., 1882

$$q_{\text{lim}} = 8\pi \sqrt{\epsilon_0 \gamma} R^{3/2}$$

Surface tension

Particle charge limits

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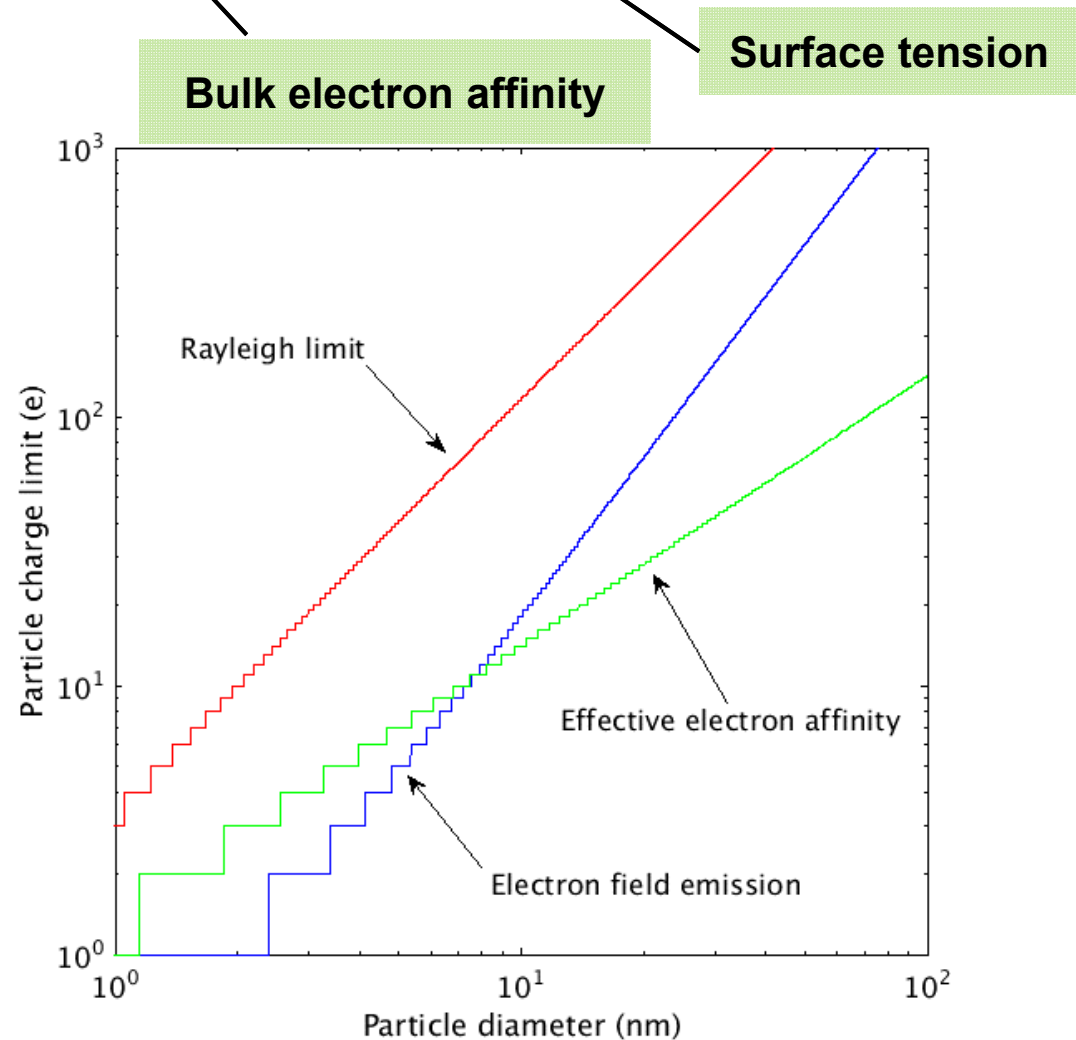
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Size dependent



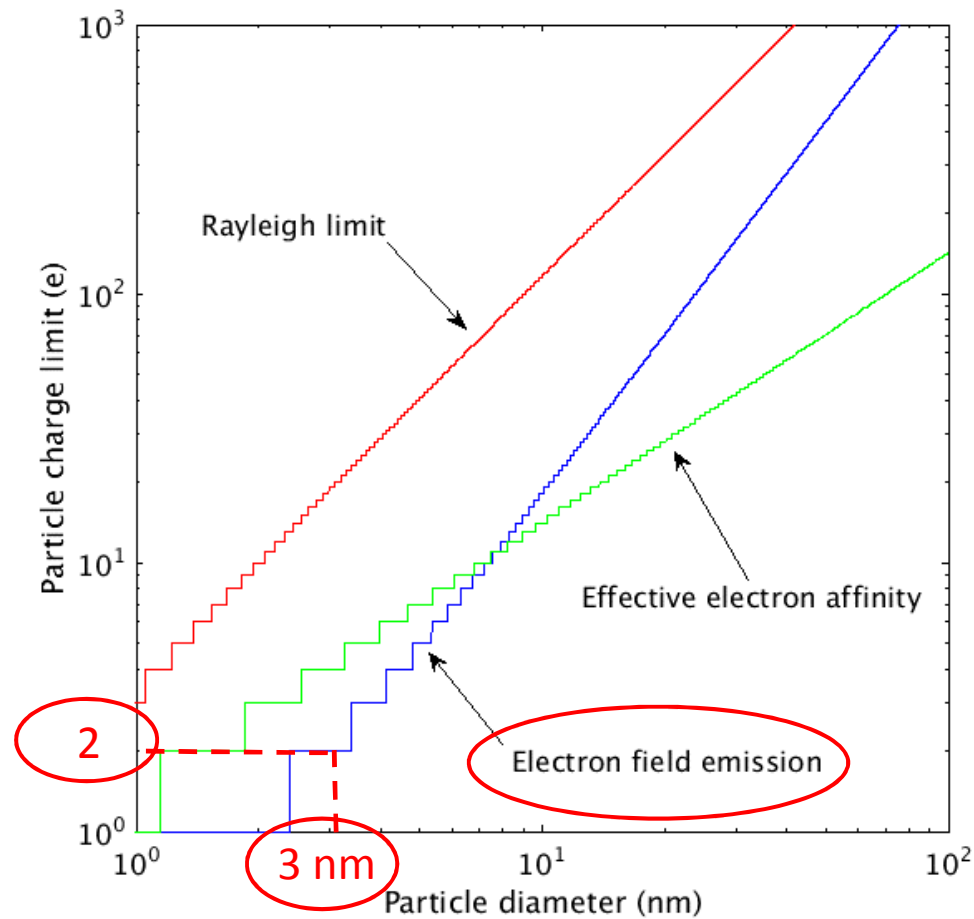
Particle charge limits

- Solid silicon particles ($A_{\infty} = 4.05 \text{ eV}$ and $\gamma > 10^{-1} \text{ N/m}$)



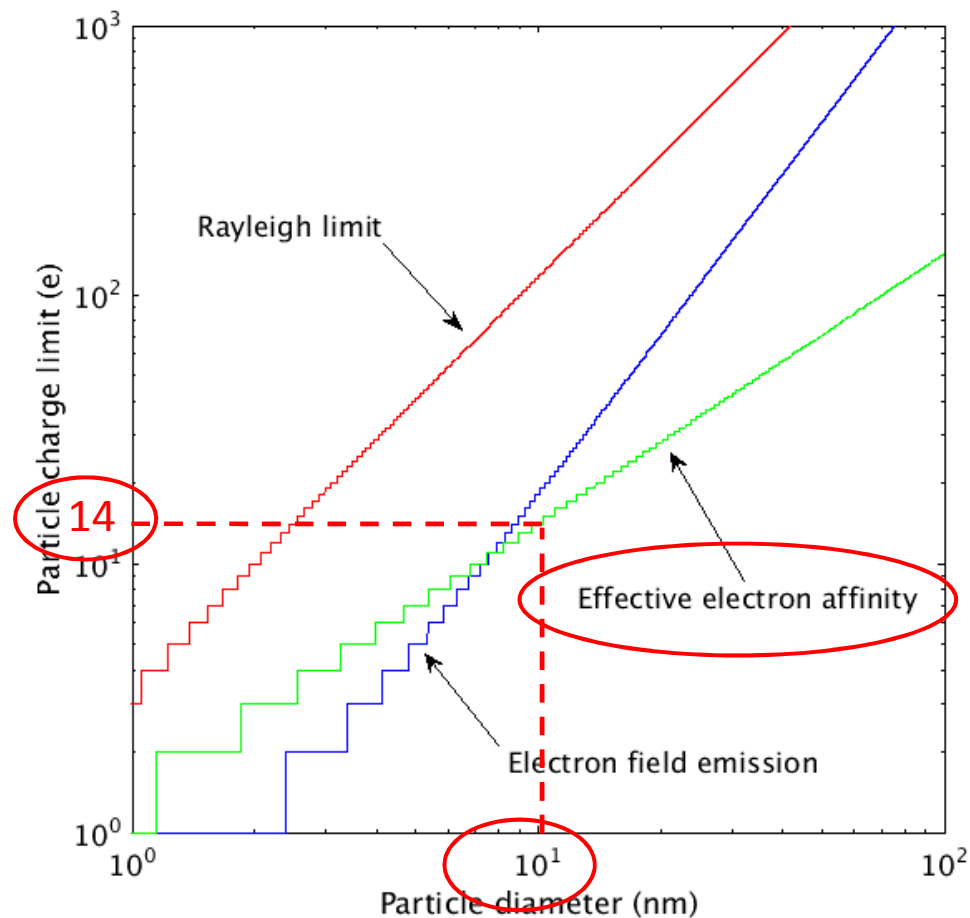
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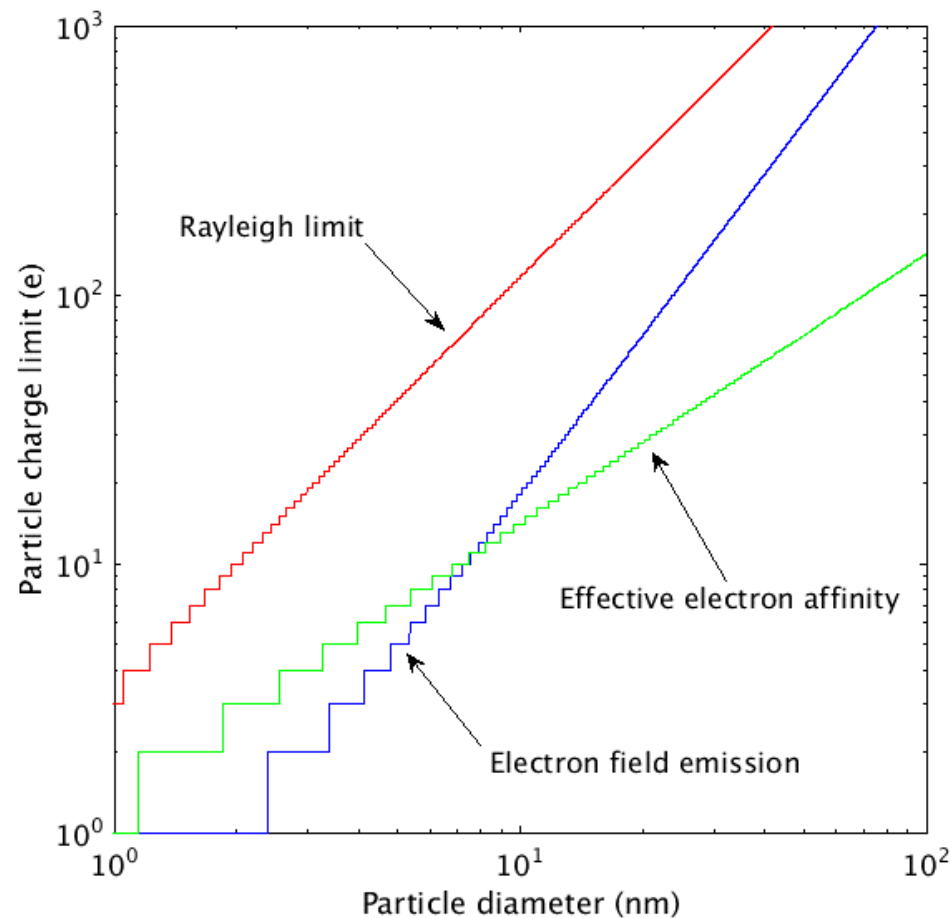
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What are effects of charge limits on particle charge distributions?

Particle charge distribution

- Analytical expression for steady-state particle charge distribution from Matsoukas and Russell (1995)

Probability distribution
for charge

$$n(q) = \frac{1}{\sigma\sqrt{2\pi}} \times \exp\left[-\frac{1}{2}\left(\frac{q - \bar{q}}{\sigma}\right)^2\right]$$

Average charge

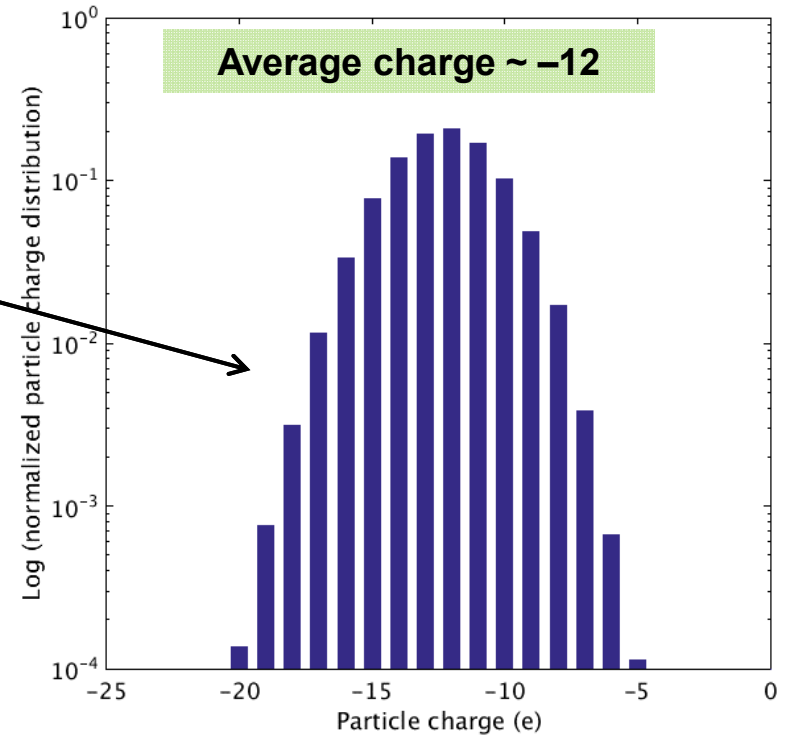
Standard deviation

- Does not take charge limits into account

Particle charge distribution

- Solid silicon nanoparticles

Charge distribution without charge limits



Simulation parameters

diameter = 5 nm

$n_e/n_i = 1$

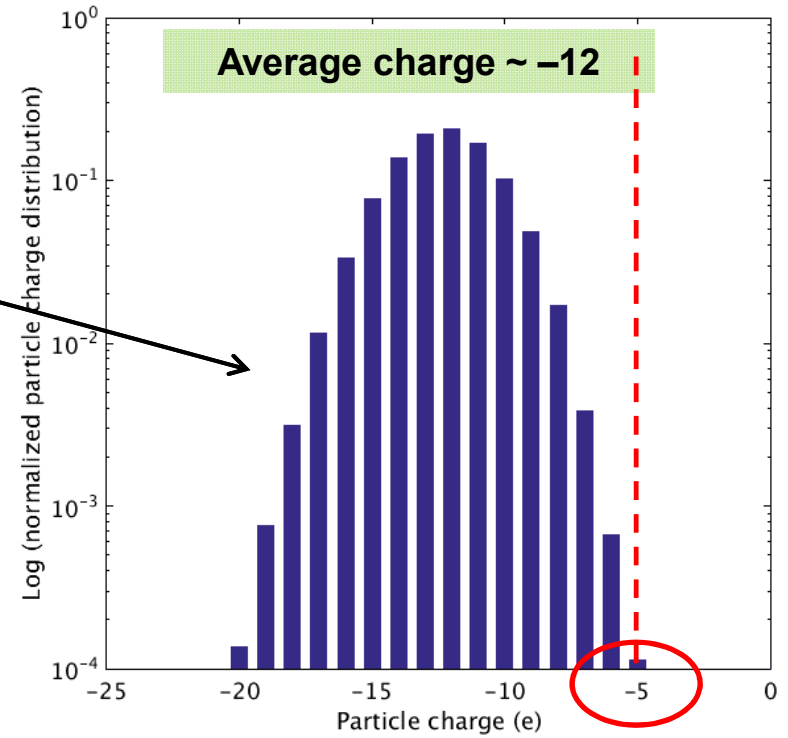
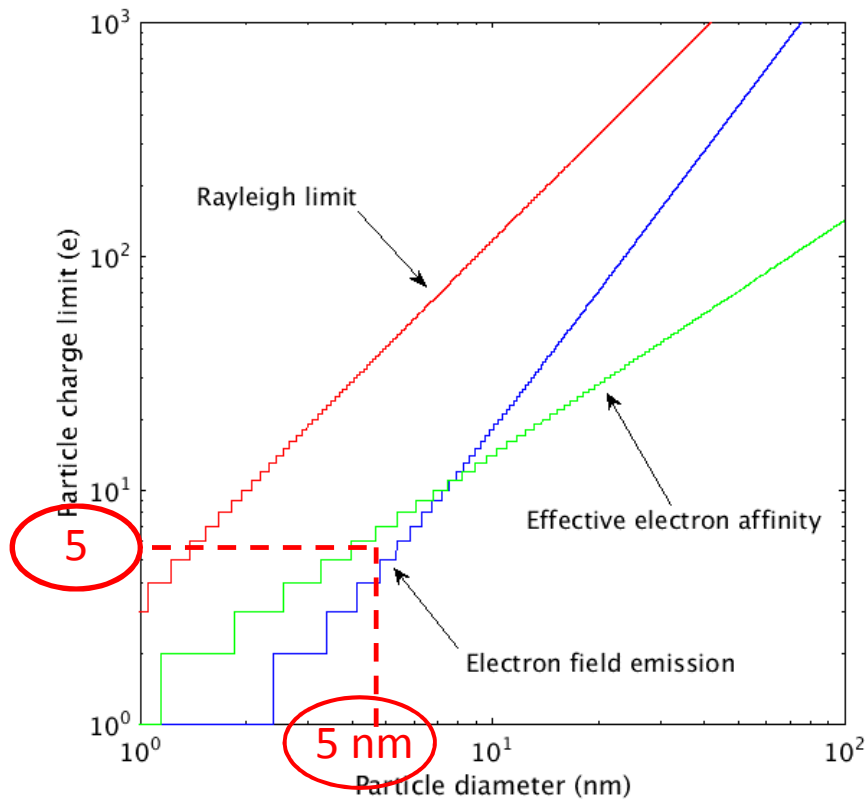
$T_e = 3$ eV

$T_i = 300$ K

Particle charge distribution

- Solid silicon nanoparticles

Charge distribution without charge limits



Simulation parameters

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$n_e/n_i = 1$

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Analytical expression

- Modifies distribution w/o charge limits by introducing correction factor
- Derivation: manuscript in preparation

Accounts for integer nature of charge $\rightarrow q'_{\text{lim}} = -q_{\text{lim}} - 0.5$

Charge distribution with charge limit

$$n^*(q) = \left[\frac{2}{1 + \operatorname{erf}\left(\frac{\bar{q} - q'_{\text{lim}}}{\sqrt{2}\sigma}\right)} \times H(q - q'_{\text{lim}}) \right] \times n(q)$$

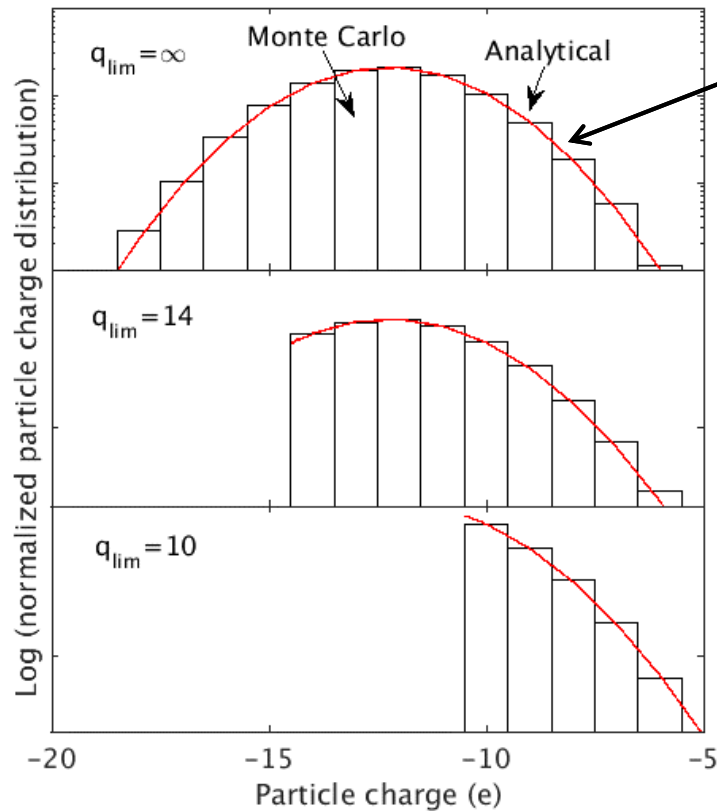
Gaussian distribution w/o charge limits

Heaviside step function

$$n^*(q) \rightarrow n(q) \text{ as } q'_{\text{lim}} \rightarrow \infty$$

Analytical expression

- Charge limit treated as free parameter
- Excellent agreement between new analytical expression & Monte Carlo simulations



Gaussian distribution

Simulation parameters

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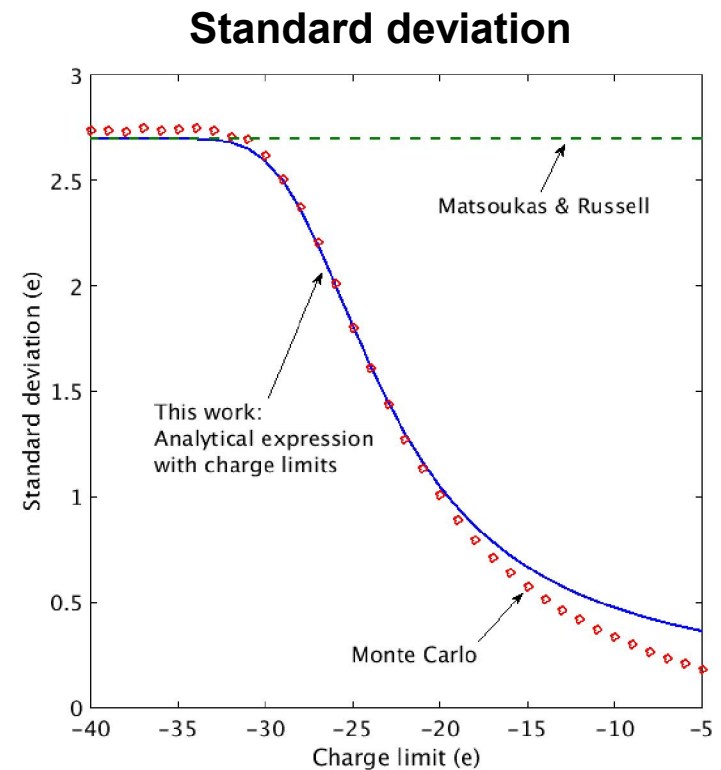
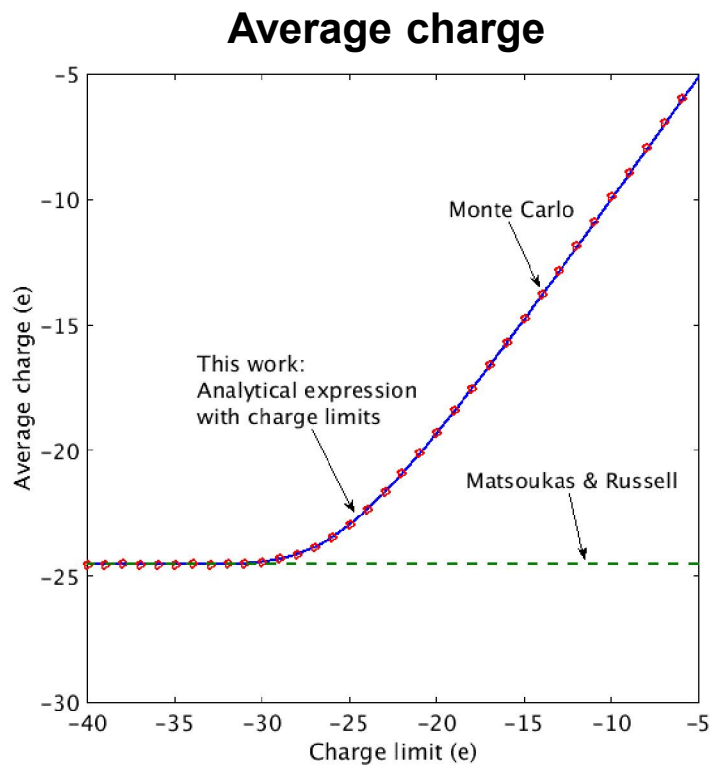
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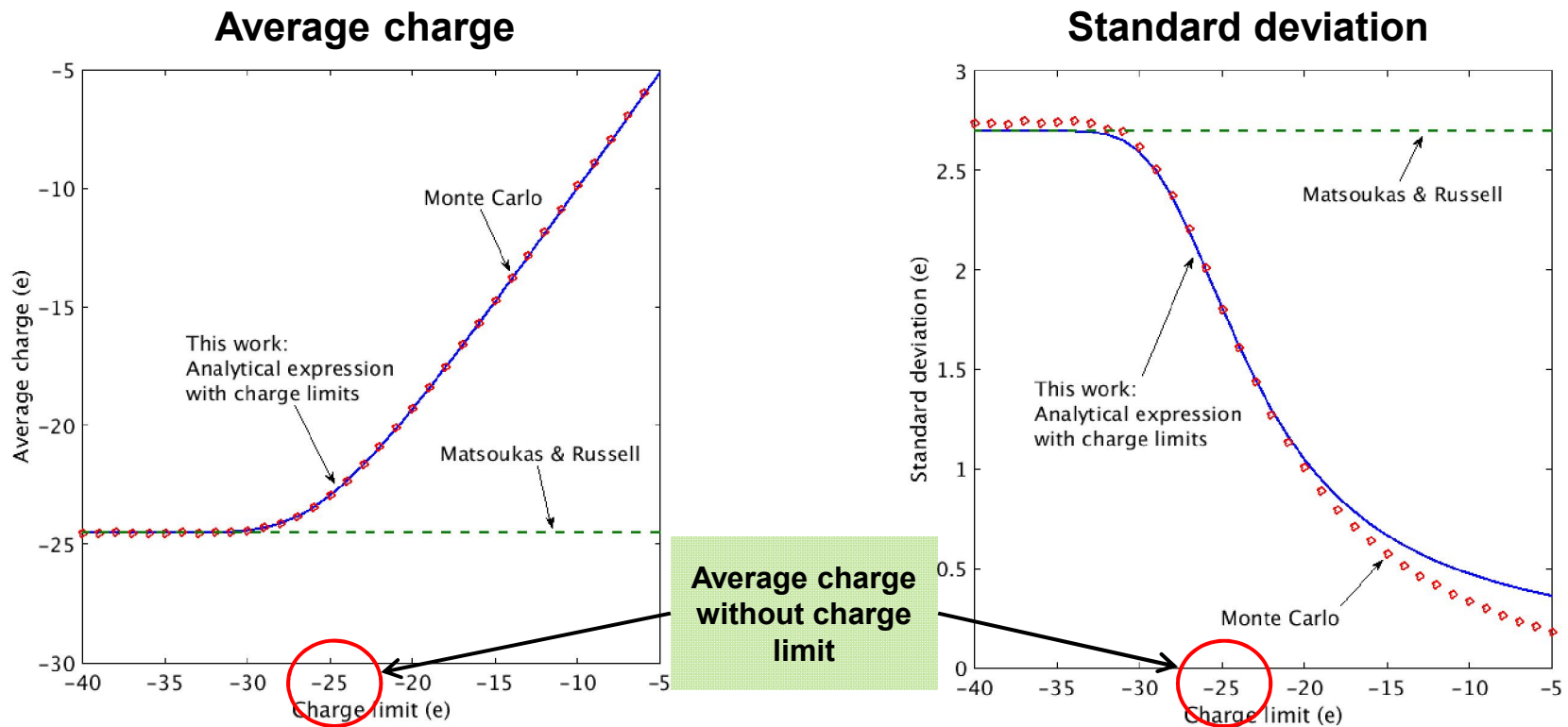
Average charge & standard deviation

- Charge limit treated as free parameter
- Excellent agreement for average charge
- Discrepancies in standard deviation at very small charge limit



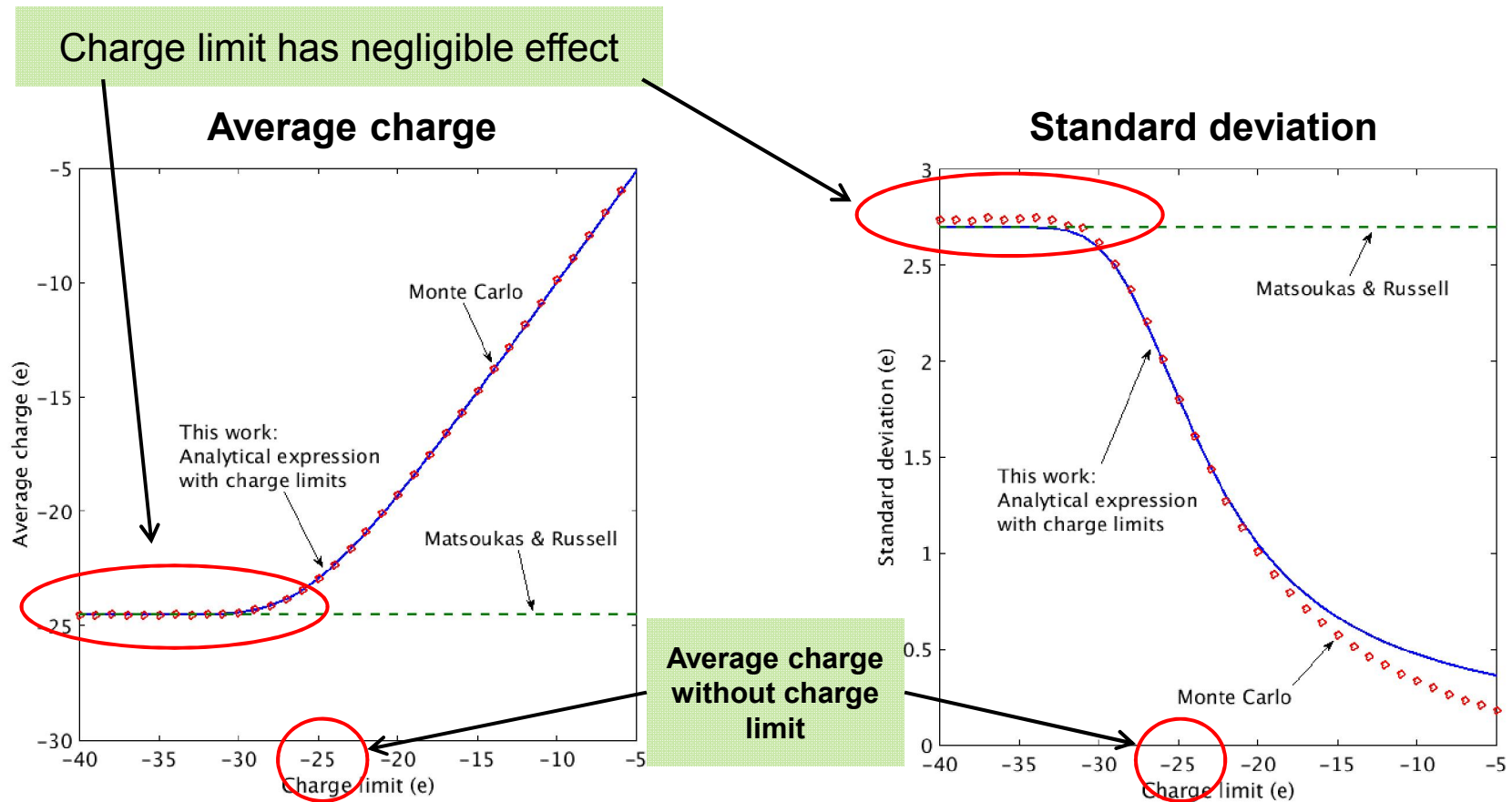
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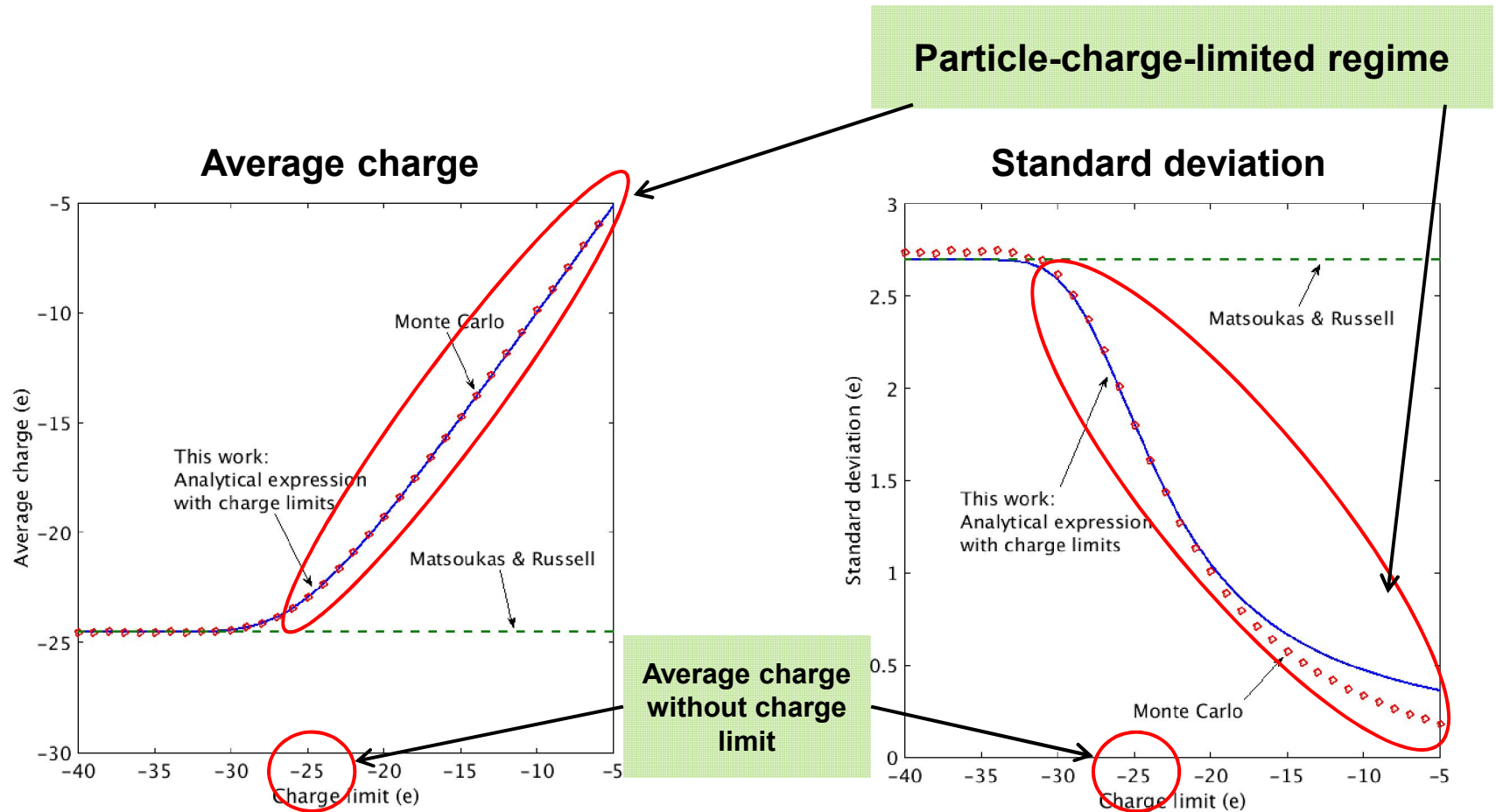
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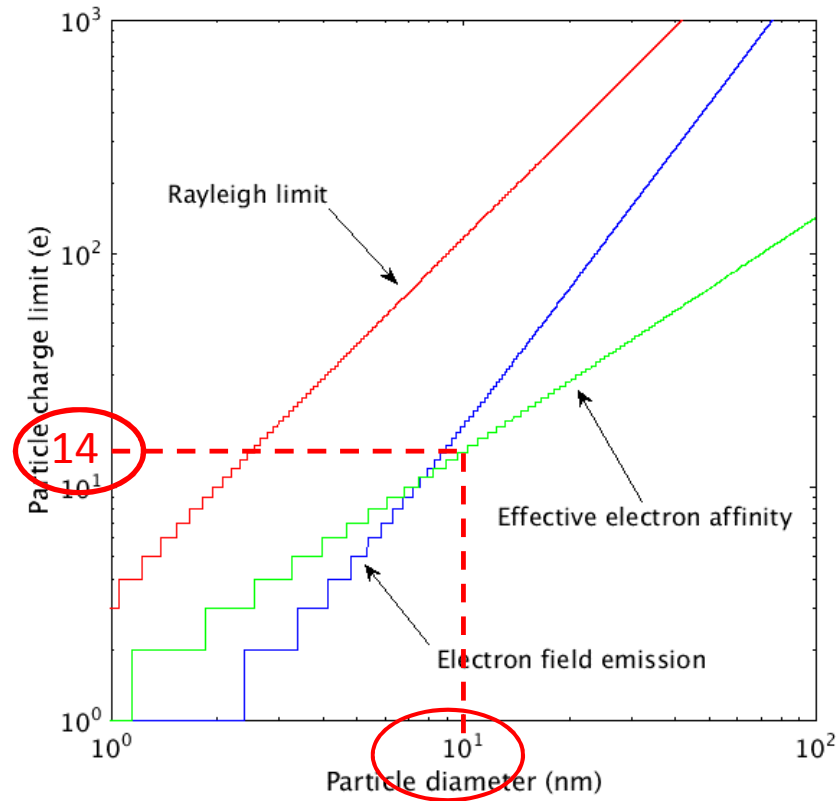
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Electron-to-ion density ratio

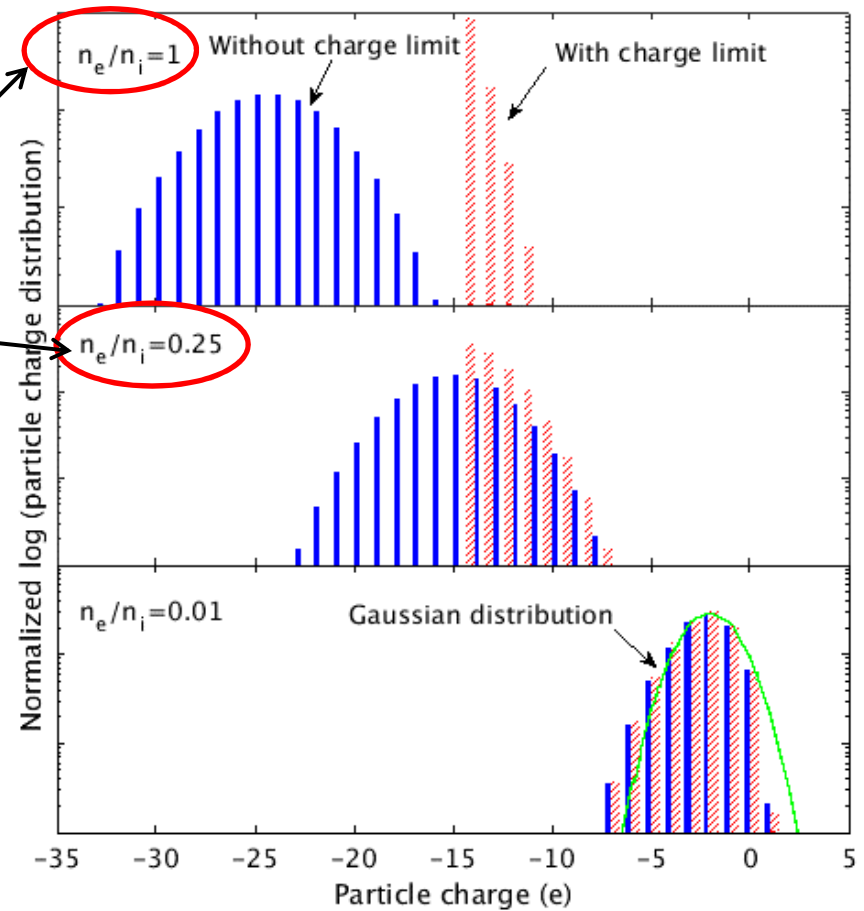
- Dust particles deplete electrons
- Silicon nanoparticles of 10-nm diameter
- Charge limit = 14



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Particle-charge-limited regime

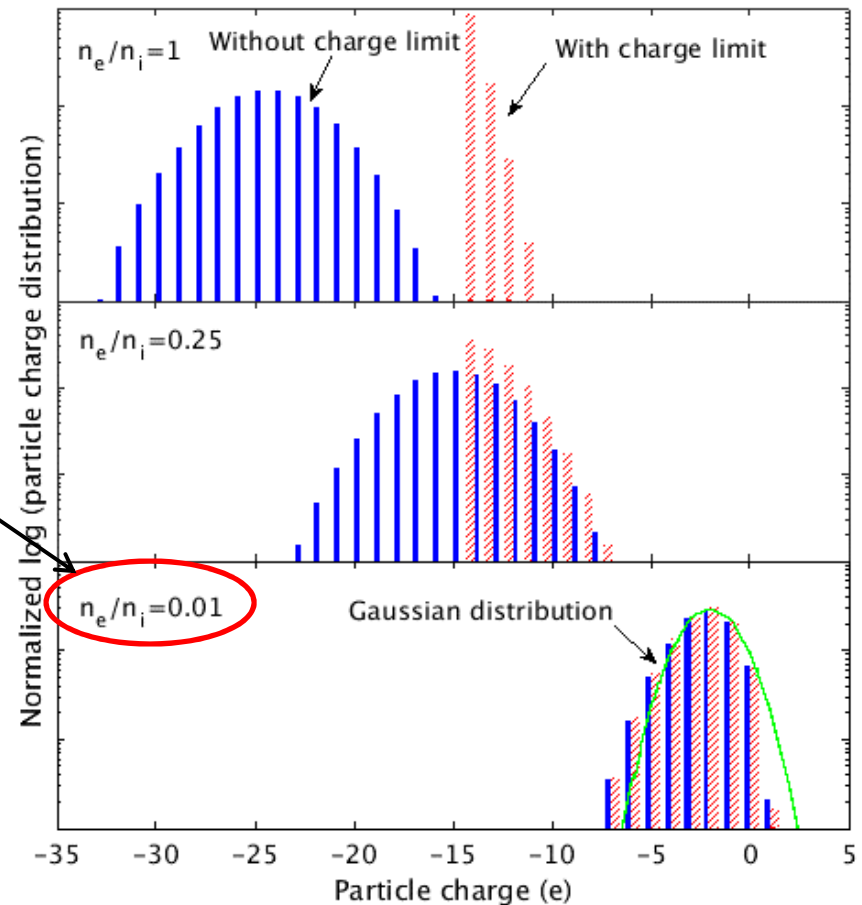


Electron-to-ion density ratio

- Dust particles deplete electrons
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Negligible effect of charge limits

- Strong electron depletion
- Deviation from Gaussian
- Assumption that particles are isolated is not valid at small n_e/n_i

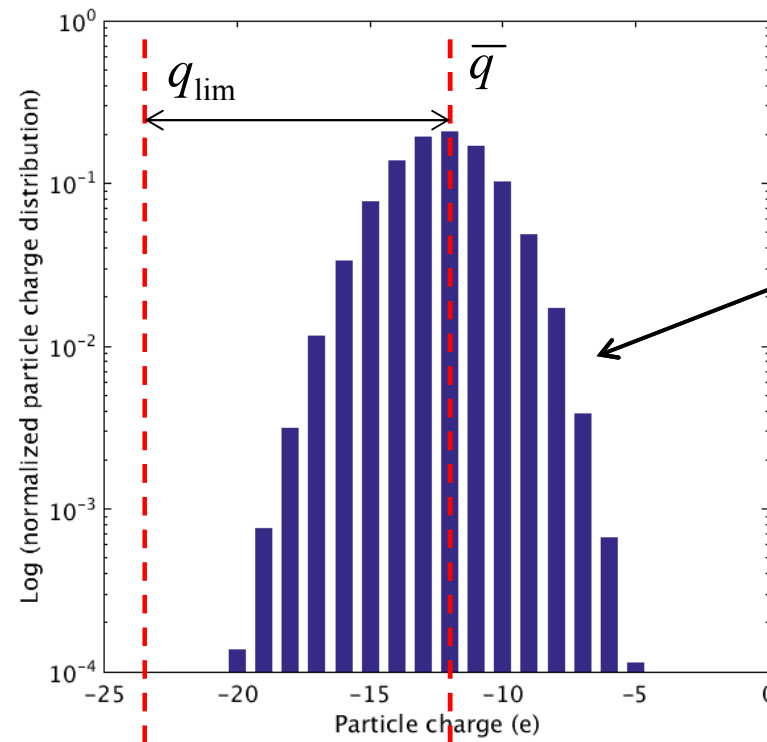


Criterion for particle-charge-limited regime

- Depends on plasma parameters and charge limit

$$q_{\text{lim}} > |\bar{q} - r\sigma|$$

Number of standard deviations



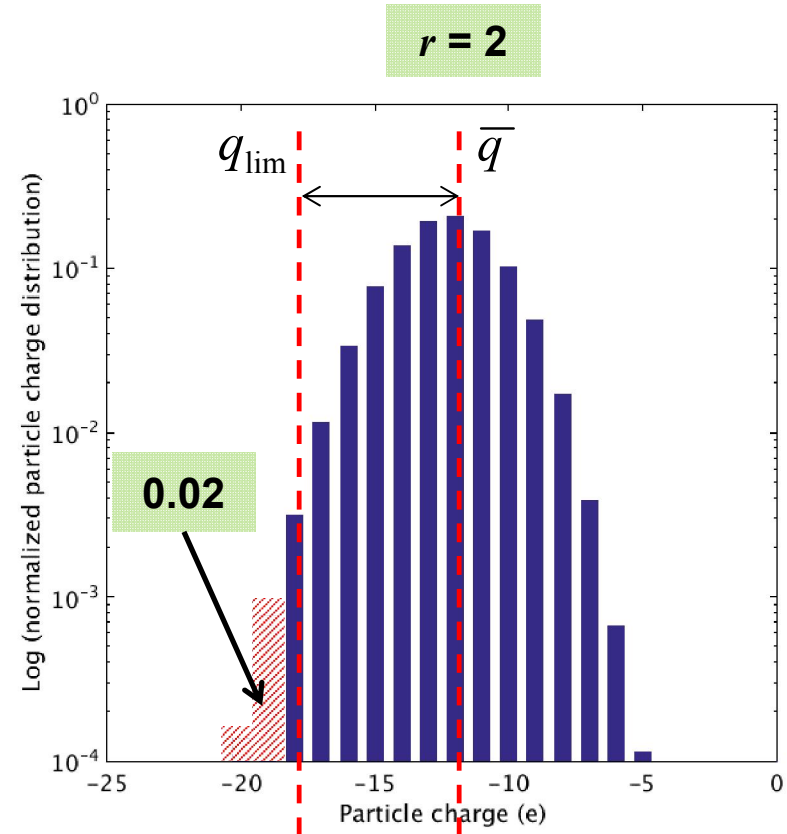
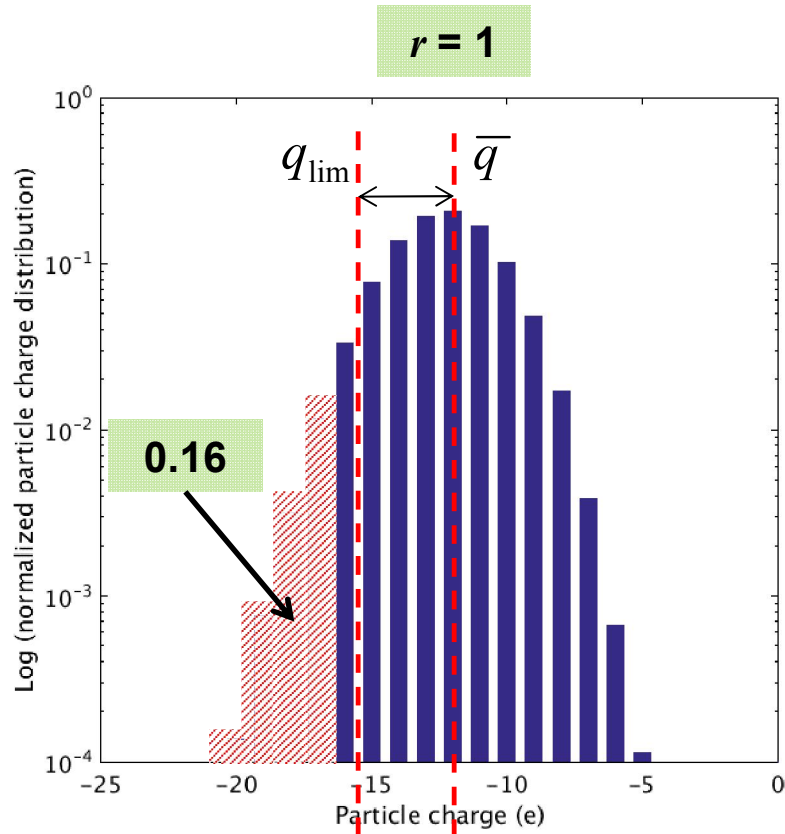
Charge distribution w/o charge limits

Criterion for particle-charge-limited regime

- Depends on plasma parameters and charge limit

$$q_{\text{lim}} > \left| \bar{q} - r\sigma \right|$$

Number of standard deviations



Conclusions

- Developed new analytical expression for stationary charge distributions accounting for particle charge limits
- Excellent agreement with Monte Carlo charging model
- Developed criterion for whether one is in the particle-charge-limited regime